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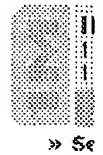
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 Hallal, H.H.; Alikacem, E.; Tunney, W.P.; Boroday, S.; Petrenko, A.;
 Quality Software, 2004. QSIC 2004. Proceedings. Fourth International Conference on , 8-9 Sept. 2004
 Pages:258 - 267

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